Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSV)

2SK3117

Chopper Regulator DC-DC Converter, and Motor Drive Applications

• Low drain–source ON resistance $: R_{DS} (ON) = 0.21 \Omega (typ.)$ • High forward transfer admittance $: |Y_{fs}| = 17 S (typ.)$

• Low leakage current : $IDSS = 100 \mu A (max) (VDSS = 500 V)$

• Enhancement-mode : $V_{th} = 2.0 \sim 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

Maximum Ratings (Ta = 25°C)

Characteris	stics	Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	500	V	
Drain-gate voltage (Ro	_{SS} = 20 kΩ)	V_{DGR}	500	V	
Gate-source voltage		V_{GSS}	±30	V	
Drain current	DC (Note 1)	I _D	20	Α	
	Pulse (Note 1)	I _{DP}	80	Α	
Drain power dissipation	n (Tc = 25°C)	P_{D}	150	W	
Single pulse avalanche	e energy (Note 2)	E _{AS}	960	mJ	
Avalanche current		I _{AR}	20	Α	
Repetitive avalanche e	nergy (Note 3)	E _{AR}	15	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature ra	ange	T _{stg}	-55~150	°C	

1. GATE 2. DRAIN (HEAT SINK) 3. SOURCE JEDEC JEITA TOSHIBA 15.9MAX. 1. 00

Weight: 4.6 g (typ.)

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	0.833	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	50	°C/W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2: V_{DD} = 90 V, T_{ch} = 25°C (initial), L = 4.08 mH, R_G = 25 Ω , I_{AR} = 20 A

Note 3: Repetitive rating; Pulse width limited by maximum channel temperature.

This transistor is an electrostatic sensitive device.

Please handle with caution.

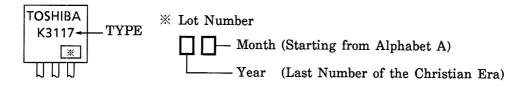
Electrical Characteristics (Ta = 25°C)

Charac	eteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I _{GSS}	V _{GS} = ±25 V, V _{DS} = 0 V	_	_	±10	μΑ
Gate-source bre	eakdown voltage	V (BR) GSS	$I_G = \pm 10 \ \mu A, \ V_{DS} = 0 \ V$	±30	_	_	V
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 500 V, V _{GS} = 0 V	_	_	100	μA
Drain-source br voltage	eakdown	V _{(BR) DSS}	I _D = 10 mA, V _{GS} = 0 V	500	_	l	V
Gate threshold v	oltage	V_{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source O	N resistance	R _{DS (ON)}	V _{GS} = 10 V, I _D = 10 A	_	0.21	0.27	Ω
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 10 A	10	17		S
Input capacitano	e	C _{iss}		_	3720	_	
Reverse transfer capacitance		C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	340	_	pF
Output capacitance		Coss		_	1165	_	
Switching time	Rise time	tr	$V_{GS} \stackrel{10V}{\underset{0V}{\longrightarrow}} \stackrel{I_{D}=10A}{\underset{R_{L}=20\Omega}{\longrightarrow}} V_{OUT}$ $V_{DD} \stackrel{:}{\rightleftharpoons} 200V$ $Duty \leq 1\%, \ t_{w} = 10 \mu s$	_	30	_	- ns
	Turn-on time	t _{on}		_	70	_	
	Fall time	t _f		_	50	_	
	Turn-off time	t _{off}		_	290	_	
Total gate charge (Gate-source plus gate-drain)		Qg		_	80	_	
Gate-source charge		Q _{gs}	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 6 \text{ A}$		48	_	nC
Gate-drain ("miller") charge		Q _{gd}			32	_	

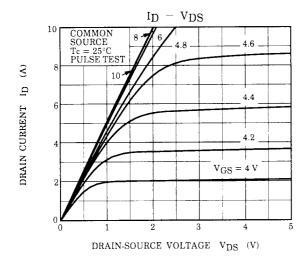
Source-Drain Ratings and Characteristics (Ta = 25°C)

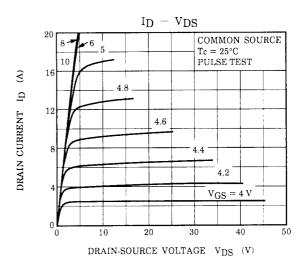
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	-	1	_	20	Α
Pulse drain reverse current (Note 1)	I _{DRP}	-	_	_	80	Α
Forward voltage (diode)	V _{DSF}	V _{DR} = 20 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 20 A, V _{GS} = 0 V		540	_	ns
Reverse recovery charge	Q _{rr}	dI _{DR} / dt = 100 A / μs	_	5.4	_	μC

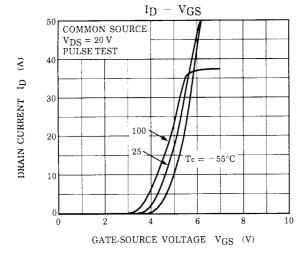
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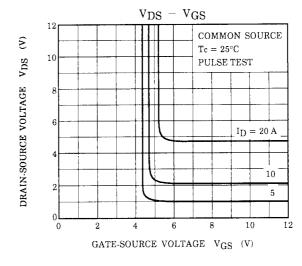


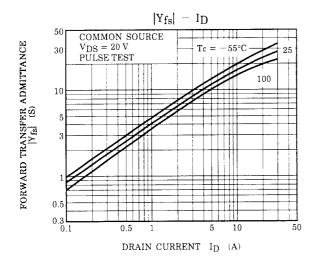
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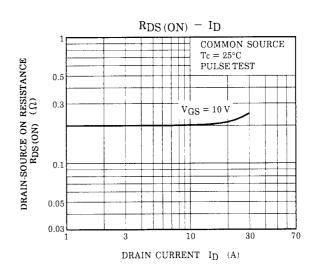




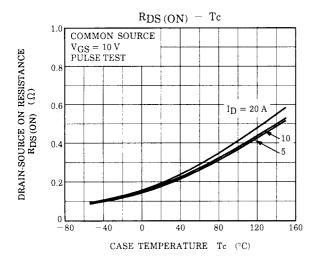


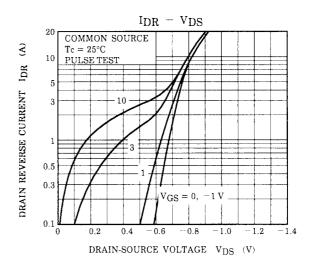


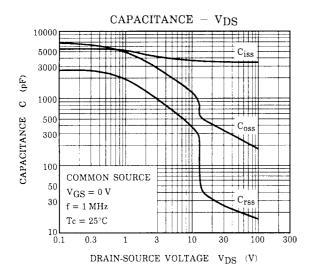


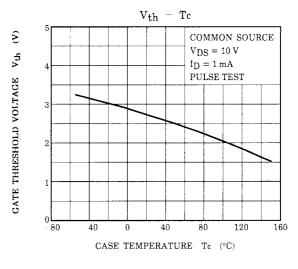


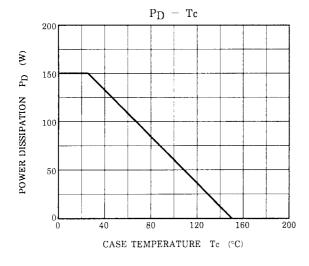
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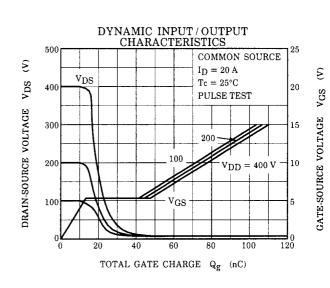




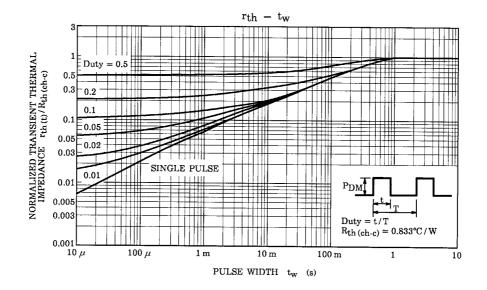


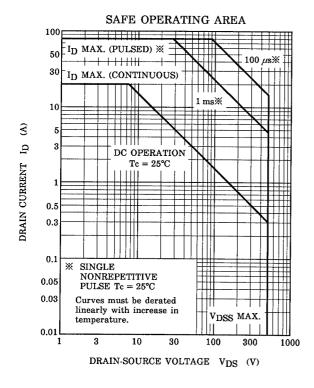


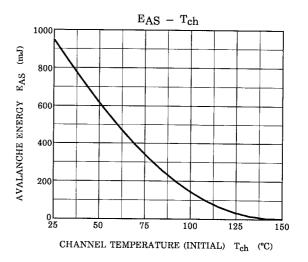


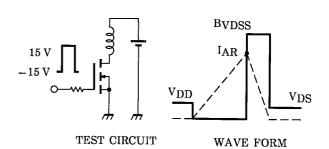


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$$\begin{aligned} &R_G = 25~\Omega \\ &V_{DD} = 90~V,~L = 4.08~mH \end{aligned} \qquad E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BV_{DSS}}{BV_{DSS} - V_{DD}} \right) \end{aligned}$$

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